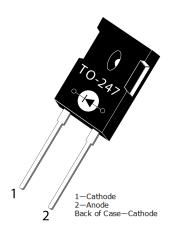


APT75DQ60BG Ultrafast Soft Recovery Rectifier Diode

1 Product Overview

This section outlines the product overview for the APT75DQ60BG device.



1.1 Features

The following are key features of the APT75DQ60BG device:

- Ultrafast recovery times
- Soft recovery characteristics
- Low forward voltage
- Low leakage current
- Avalanche energy rated
- RoHS compliant
- AEC-Q101 qualified

1.2 Benefits

The following are benefits of the APT75DQ60BG device:

- High switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

1.3 Applications

The APT75DQ60BG device is designed for the following applications:

- Power factor correction (PFC)
- Anti-parallel diode
 - Switch-mode power supply
 - Inverters/converters
 - Motor controllers
- Freewheeling diode
 - Switch-mode power supply
 - Inverters/converters
- Snubber/clamp diode



2 Electrical Specifications

This section shows the electrical specifications for the APT75DQ60BG device.

2.1 Absolute Maximum Ratings

The following table lists the absolute maximum ratings for the APT75DQ60BG device.

All ratings: Tc = 25 °C unless otherwise specified.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VR	Maximum DC reverse voltage	600	V
VRRM	Maximum peak repetitive reverse voltage	600	_
V _{RWM}	Maximum working peak reverse voltage	600	
I _{F(AV)}	Maximum average forward current (Tc = 108 °C, duty cycle = 0.5)	75	Α
I _F (RMS)	RMS forward current	117	
IFSM	Non-repetitive forward surge current (T _J = 45 °C, 8.3 ms)	600	_
Eavl	Avalanche energy (1 A, 40 mH)	20	mJ
Tл, Тsтg	Operating and storage temperature range	-55 to 175	°C
Tι	Lead temperature for 10 seconds	300	

The following table shows the thermal and mechanical characteristics of the APT75DQ60BG device.

Table 2 • Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit
Rejc	Junction-to-case thermal resistance			0.34	°C/W
Wt	Package weight		0.22		OZ
			6.2		g
	Maximum mounting torque			10	lbf∙in
				1.1	N∙m

2.2 Electrical Performance

The following table lists the static characteristics of the APT75DQ60BG device.

Table 3 • Static Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
VF	Forward voltage	I _F = 75 A		2.0	2.5	_ V _
		I _F = 150 A		2.4		
		I _F = 75 A, T _J = 125 °C		1.7		
IRM	Maximum reverse leakage current	V _R = 600 V			25	μΑ
		V _R = 600 V, T _J = 125 °C			500	_
Cı	Junction capacitance	V _R = 200 V		110		pF



2.3 Dynamic Characteristics

The following table lists the dynamic characteristics of the APT75DQ60BG device.

Table 4 • Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Uni
trr	Reverse recovery time	I _F = 1 A		29		ns
		$di_F/dt = -100 A/\mu s$				
		$V_R = 30 \text{ V}$				
		T _J = 25 °C				
trr	Reverse recovery time	I _F = 75 A		31		-
Qrr	Reverse recovery change	— di _F /dt = -200 A/μs V _R = 400 V		55		nC
IRRM	Maximum reverse recovery current	T _c = 25 °C	-	4		Α
trr	Reverse recovery time	I _F = 75 A		140		ns
Qrr	Reverse recovery charge	di _F /dt = -200 A/μs V _R = 400 V T _C = 125 °C		650		nC
IRRM	Maximum reverse recovery current			9		Α
trr	Reverse recovery time	I _F = 75 A		90		ns
Qrr	Reverse recovery change	di _F /dt = -1000 A/μs V _R = 400 V		1300		nC
Irrm	Maximum reverse recovery current	Tc = 125 °C		27		Α

2.4 Typical Performance Curves

This section shows the typical performance curves for the APT75DQ60BG device.

Figure 1 • Maximum Transient Thermal Impedance

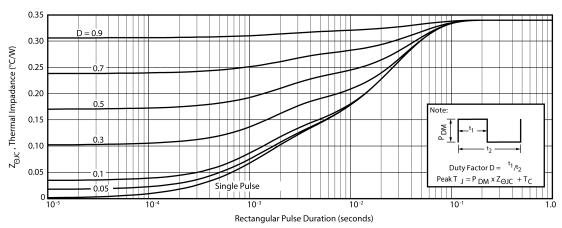




Figure 2 • Forward Current vs. Forward Voltage

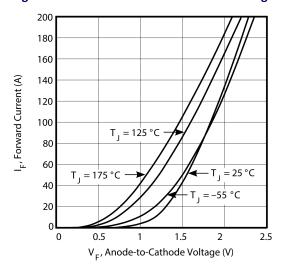


Figure 4 • Reverse Recovery Charge vs. Current Rate of Change

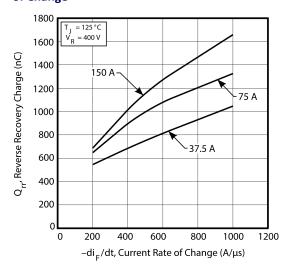


Figure 3 • RRT vs. Current Rate of Change

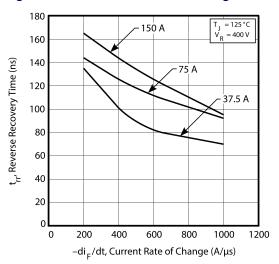


Figure 5 • Reverse Recovery Current vs. Current Rate of Change

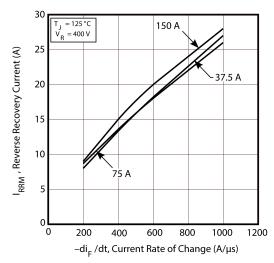




Figure 6 • Dynamic Parameters vs. Junction Temperature

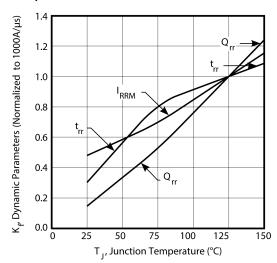


Figure 7 • Maximum Average Forward Current vs. Case Temperature

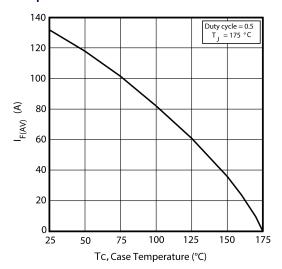
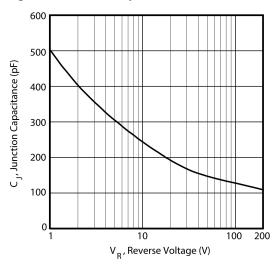


Figure 8 • Junction Capacitance vs. Reverse Voltage

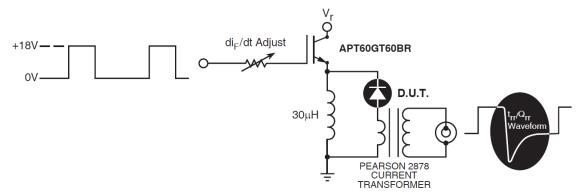




2.5 Reverse Recovery Overview

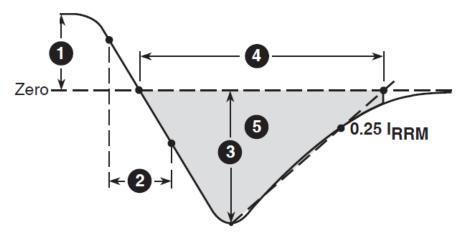
The following figure illustrates the diode test circuit for the APT75DQ60BG device.

Figure 9 • Diode Test Circuit



The following figure illustrates the diode reverse recovery waveform and definitions for the APT75DQ60BG device.

Figure 10 ● Diode Reverse Recovery Waveform and Definitions



- 1. IF—Forward conduction current.
- 2. di_F/dt—Rate of diode current change through zero crossing.
- 3. IRRM—Maximum reverse recovery current.
- 4. trr—Reverse recovery time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through IRRM and 0.25 IRRM passes through zero.
- 5. Qrr—Area under the curve defined by IRRM and trr.



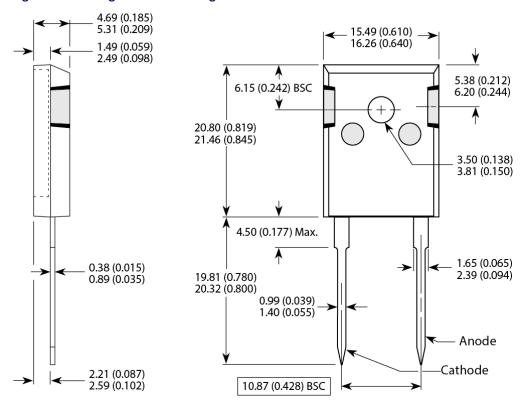
3 Package Specification

This section shows the package specification for the APT75DQ60BG device.

3.1 Package Outline Drawing

The following figure illustrates the TO-247 package outline of the APT75DQ60BG device. Dimensions are in millimeters and (inches).

Figure 11 • Package Outline Drawing







Microsemi Headquarters

One Enterprise, Aliso Viejo, CA 92656 USA Within the USA: +1 (800) 713-4113 Outside the USA: +1 (949) 380-6100 Sales: +1 (949) 380-6136 Fax: +1 (949) 215-4996 Email: sales.support@microsemi.com

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053-4209 | March 2019 | Final